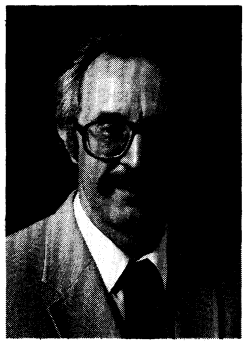
Journal of Electronic Imaging

EDITORIAL



Edward R. Dougherty
Editor

The Electronic Imaging Symposium in San Jose was a great success. There were 20 conferences covering major areas of electronic imaging: color hard copy, displays, image capture, image processing, multimedia systems, and vision and visualization. Working group meetings were held for Holography and Electronic Imaging, with the latter being dedicated to real-time image processing. There were 28 short courses covering CCDs, displays, document imaging, electronic imaging systems, and image, video, and multimedia processing. In speaking with the chairs of a number of the conferences, I found that they were pleased with the general quality of the presentations. As for Nonlinear Image Processing, a conference I have co-chaired for a number of years, I believe that the overall quality of the presentations surpassed all of the previous conferences. For the one conference there were contributors from 13 countries, including four from the former Soviet Union.

Among the hundreds of papers presented for the symposium as a whole, there are many that concern studies that are near or at the point where they can be readied for publication in an archival, refereed journal. During the symposium I took time to meet with a number of conference chairs to ask their assistance in identifying papers. This is not an easy task, nor one that is always possible, given the brevity of the presentations and the amount of coming and going required of conference chairs. I now extend to all participants in EI'95 an invitation to prepare full, extended papers based on completed work that you believe is sufficiently novel, in-depth, and scientifically significant to warrant submission to the *Journal of Electronic Imaging* for full peer review and possible acceptance for publication in the journal.

It is important for both sponsoring societies, IS&T and SPIE, that there be synergy between the symposium and the journal. It is in the very nature of a scientific society that new work be presented in brief at symposia and that some of that work go on to sufficient development to reach peer-reviewed publication. Societies represent and are composed of members who participate in activities such as symposia, working groups, and journals. It is important for each of us that a synergy evolve between the electronic image symposium and the journal. In the ebb and flow of scientific understanding, new ideas emerge, they are presented, they are published in full, and (from those ideas) new ideas emerge. Together, the symposium and the journal can facilitate this movement and provide a common ground for expansion of knowledge beneficial for individuals and the industry as a whole.

The *Journal of Electronic Imaging* is committed to the widest possible excursions in electronic imaging. As societies, both SPIE and IS&T are expansive, their memberships, participants, and activities including scientists, engineers, and mathematicians from industry, academia, and government. The *Journal of Electronic Imaging* is committed to this expansive policy and I hope that the mix of papers will expand even wider during my editorship, while at the same time maintaining a high caliber of papers. Attainment of this goal requires a steady stream of quality papers from the various areas encompassed by electronic imaging. It is only natural that a goodly portion of these papers should originate in the electronic imaging symposium.

Let me close by saying that we are well on our way to having a number of special sections in the journal, commencing with the first issue in 1996. Five are already planned and announced (see the Editorial Schedule on the next page). These specials take us through the first issue of 1997. We hope to have two or three more for 1997.

EDITORIAL SCHEDULE

January 1996

Digital Document Imaging

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This special section will cover image processing topics that are relevant to creation, acquisition, storage, transmission, recognition, analysis, and rendering of digital documents. Specific topics of interest are OCR, compression, document structure analysis, digital magnification, resolution conversion, enhancement, restoration, halftoning, and color management.

Manuscripts due May 1, 1995.

April 1996

Multimedia Systems

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Manuscripts due Aug. 1, 1995

July 1996

Nonlinear Image Processing

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Real-Time Imaging

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January 1997

Random Models in Imaging

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